

## D. Thin Film Process Technology **분과**

2017년 2월 15일 (수), 08:30-10:00

Room A (에메랄드, 2층)

### [WA1-D] Thin Films for Memories and Transistors

좌장: 최창환(한양대학교)

<b>WA1-D-1</b> 08:30-08:45	<b>Development of a Reduction-Resistant Oxide Electrode for Dynamic Random Access Memory Capacitor</b> Cheol Jin Cho <sup>1,2</sup> , Jin-Sang Kim <sup>1</sup> , Cheol Seong Hwang <sup>2,3</sup> , and Seong Keun Kim <sup>1</sup> <i><sup>1</sup>Center for Electronic Materials, Korea Institute of Science and Technology,</i> <i><sup>2</sup>Department of Materials Science and Engineering, Seoul National University,</i> <i><sup>3</sup>Inter-University Semiconductor Research Center, Seoul National University</i>
<b>WA1-D-2</b> 08:45-09:00	<b>The Influence of Ti Buffer Layer on the Cu-Se Based Atomic Switch</b> Hyun suk Woo and Sanghun Jeon <i>Department of Applied Physics, Korea University</i>
<b>WA1-D-3</b> 09:00-09:15	<b>Novel Forming-Free and Multilevel Resistive Switching Device with SiO<sub>x</sub>/ZnO Thin Film Oxide Heterostructures</b> Andrey Sokolov Sergeevich, Seokki Son, Donghwan Lim, Youngjin Kim, Hoonhee Han, Jaeho Lee, Yu-Rim Jeon, and Changhwan Choi <i>Division of Materials Science and Engineering, Hanyang University</i>
<b>WA1-D-4</b> 09:15-09:30	<b>Low-Temperature Annealing Effects on the Memory Retention Properties of the Oxide Memory TFTs Using ZnO Nanoparticle Charge-Trap Sites</b> Gi-Ho Seo and Sung-Min Yoon <i>Kyung Hee University</i>
<b>WA1-D-5</b> 09:30-09:45	<b>Improvement in Gas Sensing Response via Introduction of ALD-Grown ZnO Nanoparticles with Top-Gate In-Ga-Zn-O Thin-Film Transistor</b> Da-Jeong Yun, Gi-Ho Seo, Won Ho Lee, and Sung-min Yoon <i>Department of Advanced Materials Engineering for Information and Electronics, Kyung Hee University</i>